Test Report issued under the responsibility of:





TEST REPORT

IEC 609//-2

Low-voltage switchgear and cont of ar - Part 2. Circuit-breakers

Date of issue 2019-08-12

Total number of pages 227

Co., Ltd. (STIEE)

Address 505 Wu Ning Rd. Shanghai 200063, P.R. CHINA

Applicant's name...... Zhejiang Tengen Electrics Co.,Ltd.

Test specification:

Standard IEC 60947-2:2006 (Fourth Edition) + A1: 2009 + A2: 2013

Test procedure: CB scheme

Non-standard test method...... N/A

Test Report Form No...... IEC60947_2G

Test Report Form(s) Originator: DEKRA Certification BV

Master TRF Dated 2013-11

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Test item description Moulded Case Circuit Breaker

Trade Mark: TENGEN

Manufacturer: Zhejiang Tengen Electrics Co.,Ltd.

Model/Type reference TGM1N-63L/M/H/R, TGM1N-125L/M/H/R

In: TGM1N-

125L/M/H/R: 10A, 16A, 20A, 25A, 32A, 40A, 50A, 63A, 80A, 100A, 125A;

TGM1N-63L/M/H/R:10A,16A,20A,25A,32A,40A,50A,63A

Testing procedure and testing location:		
	Shanghai Testing & Inspection Institute for Electrical Equipment Co., Ltd. (STIEE)	
Testing location/ address:	505 Wu Ning Rd. Shanghai 200063, P.R. CHINA	
Tested by (name + function + signature):	Cui Tao/Engineer	流游
Approved by (+ function + signature):	Wei Qingyuan/ Senior Engineer	魏水媛
Testing procedure: TMP	N/A	
Testing location/ address:	N/A	
resting location, address	14/74	
Tested by (name + signature):	N/A	
Approved by (name + signature):	N/A	
☐ Testing procedure: WMT	N/A	
Testing location/ address:	N/A	
Tested by (name + signature):	N/A	
Witnessed by (name + signature):	N/A	
Approved by (name + signature):	N/A	
☐ Testing procedure: SMT	N/A	
Testing location/ address:	N/A	
Tested by (name + signature)::	N/A	
Approved by (name + signature):	N/A	
Supervised by (name + signature):	N/A	